

# Emerging New Technologies in Failure Analysis



Katrin Field Incorporated



De La Salle University

PHENOMWORLD

Council for Failure Analysis and Reliability



## **AM Session**

**8:30 REGISTRATION**

**9:00 National Anthem**

**Opening Prayer**

**Welcome Remarks (CFAR / KFI / DLSU)**

**9:15 “Overview of EFA Technologies for Die-Level Analysis, from Optical Fault Isolation to Nano-Probing” By Dr. Chun-Cheng Tsao,**

**10:00 Coffee Break**

**10:15 “ELITE, Lock-In Thermography Solution for Non-Destructive and Z-Depth Analysis” By David Tien**

**11:30 Possibilities in Imaging & Analysis: PhenomWorld**

**12 noon Lunch Break**

## **PM Session**

**1:00** CFAR

**1:30** Industrial Application by Atomic Force Microscopy (AFM) - Steve Ong, PhD,  
Park Systems

**2:30** Introduction of the Solid State Sample Preparation Workflow - Ms. Angela Hu,  
MS MSE, Leica Microsystems

**3:00** Coffee Break

**3:15** Break Out Sessions: Workshop/Demo with FEI, PhenomWorld, Park Systems,  
EDAX, Leica Microsystems

**5:00** End of Session